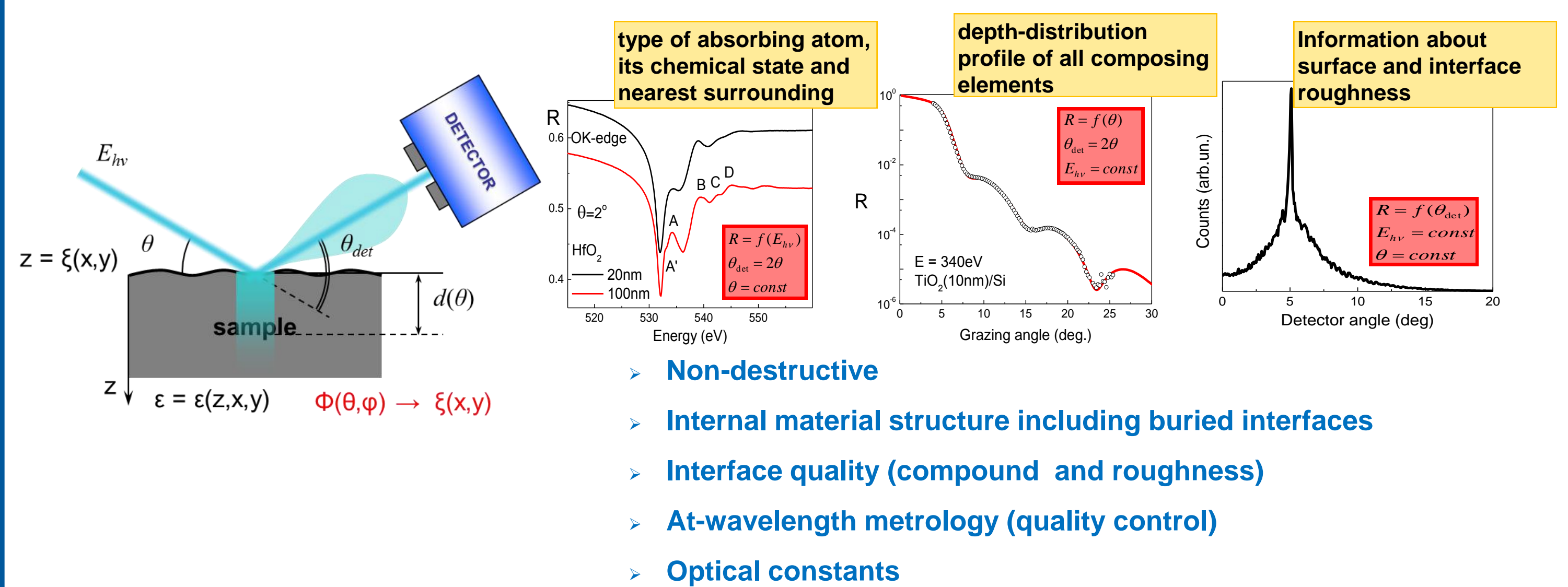


# At-Wavelength Metrology Facility for UV- and XUV Reflection and Diffraction Optics

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## Research with Reflectometry

### Reflectometry - a powerful technique



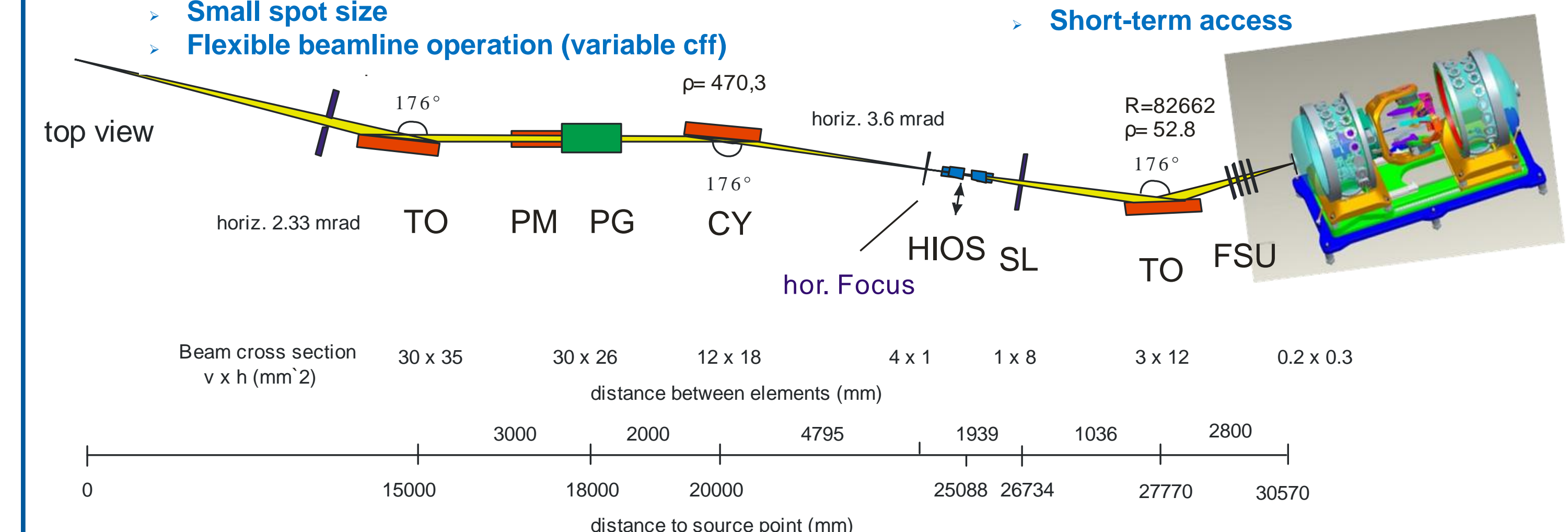
## Optics Beamline

### Collimated c-PGM

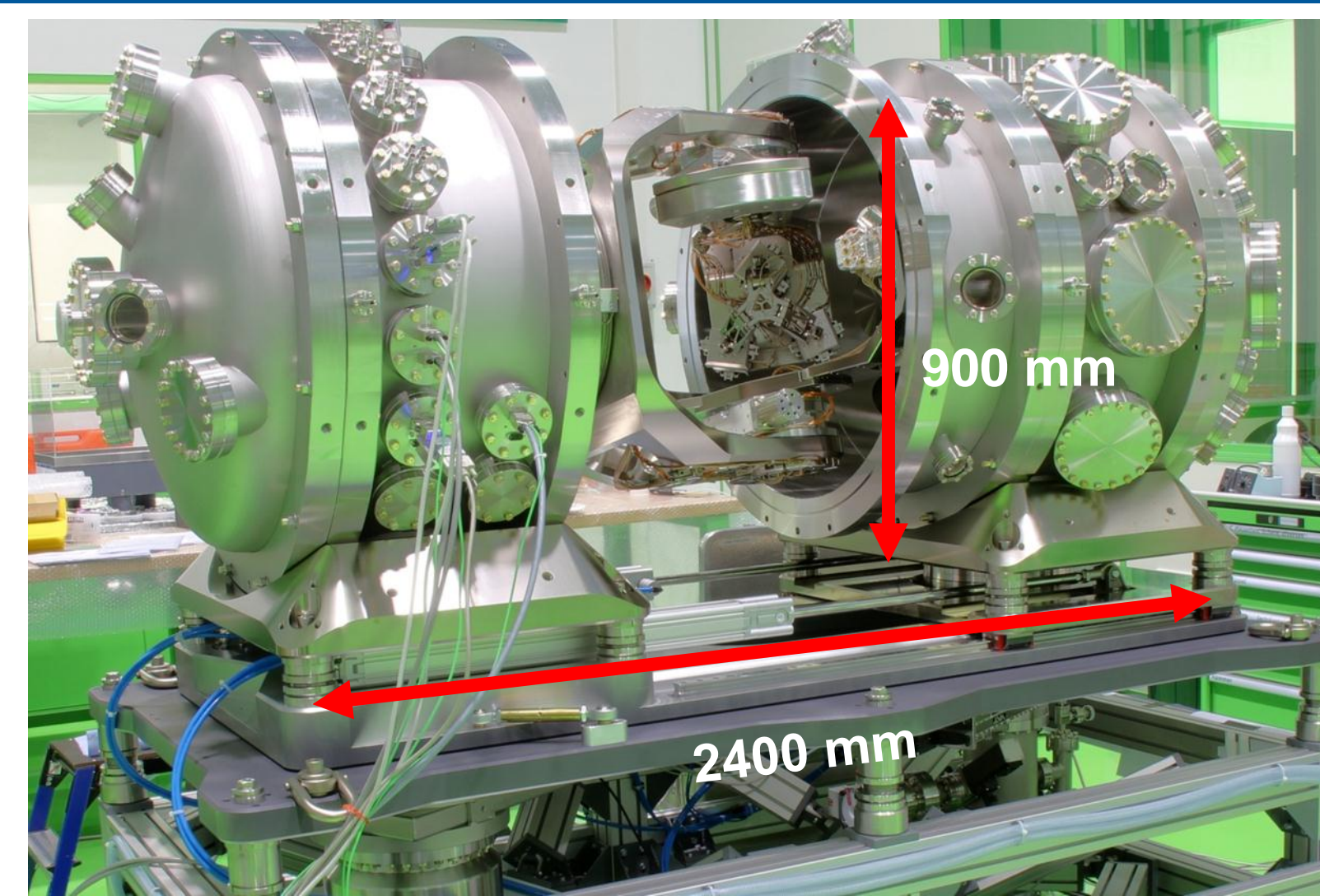
- 10 - 2000 eV
- Moderate resolution 5.000 (@400 eV)
- Polarization linear / elliptical
- Higher order suppression
- Low divergence
- Small spot size
- Flexible beamline operation (variable cff)

### Reflectometry

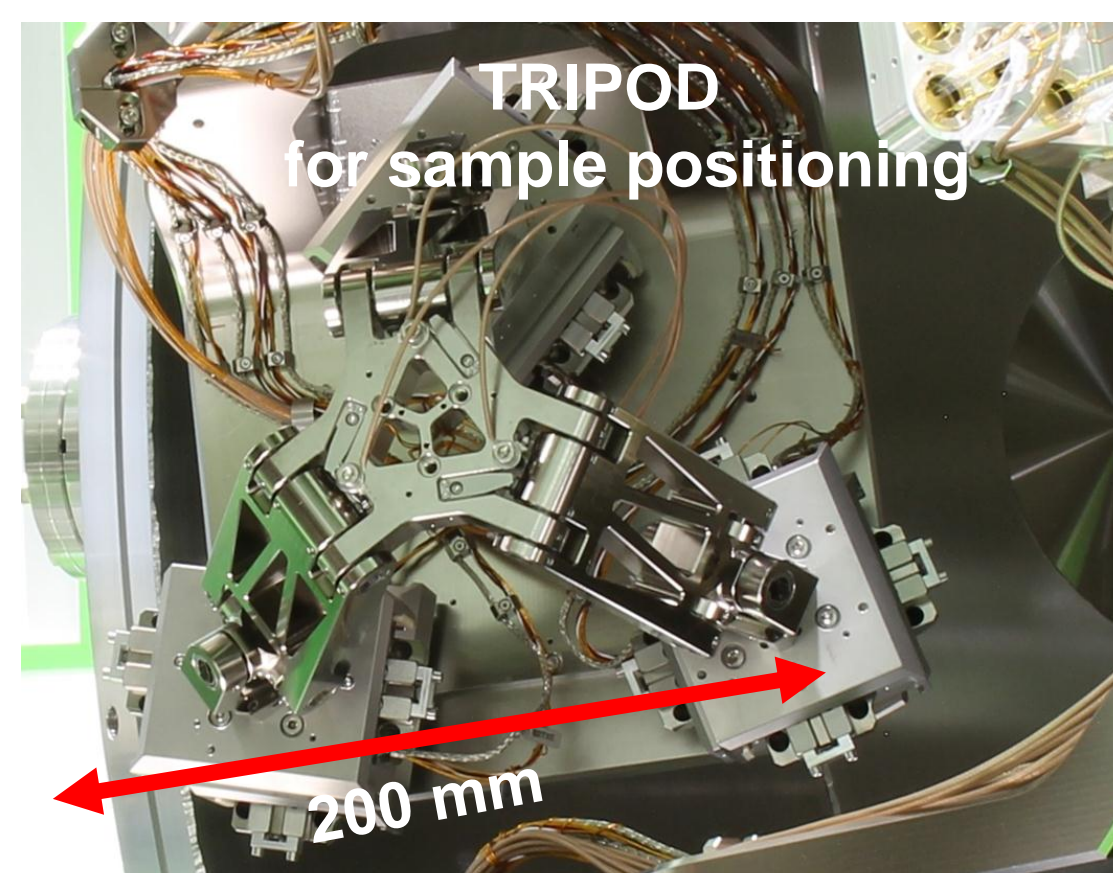
- At-wavelength metrology
- Quality control
- In-house R&D
- User operation
- Short-term access



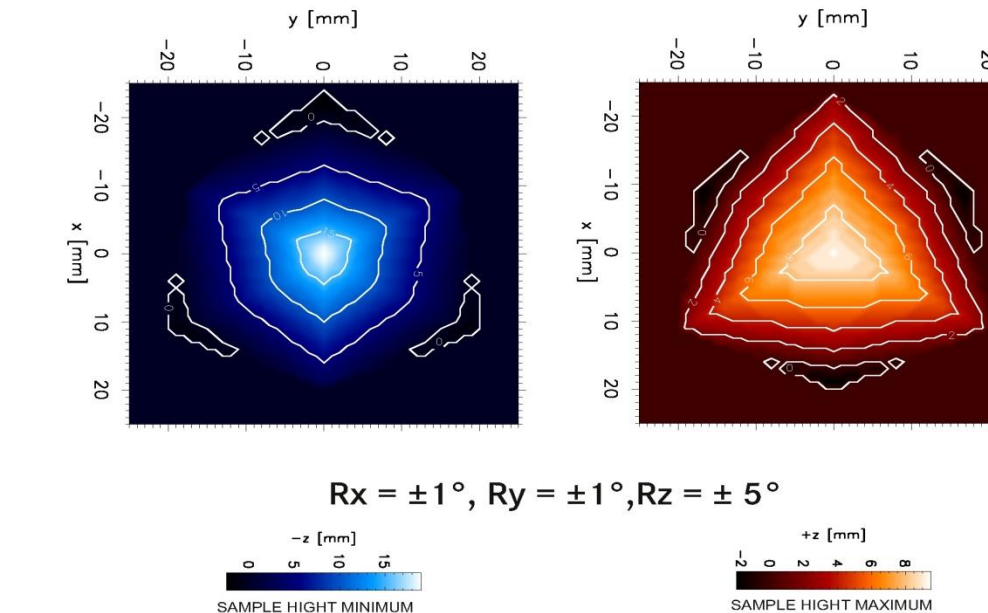
## 11 axes UHV-Reflectometer



- Clean room surrounding
- UHV-tube volume 2 m<sup>3</sup>
- Chamber weight 2.1 tons
- 2000 l/s Turbomolecular pump
- LN<sub>2</sub> cold trap, Ti-Suppl. Pump
- Base pressure <5x10<sup>-9</sup> mbar
- Pneumatic drive for chamber opening
- Renishaw encoders at all axes
- Measurements of R<sub>s</sub> and R<sub>p</sub>
- Samples electrically isolated
- Sample weight: 4 kg
- Sample size: 300 x 60 x 60 mm<sup>3</sup>



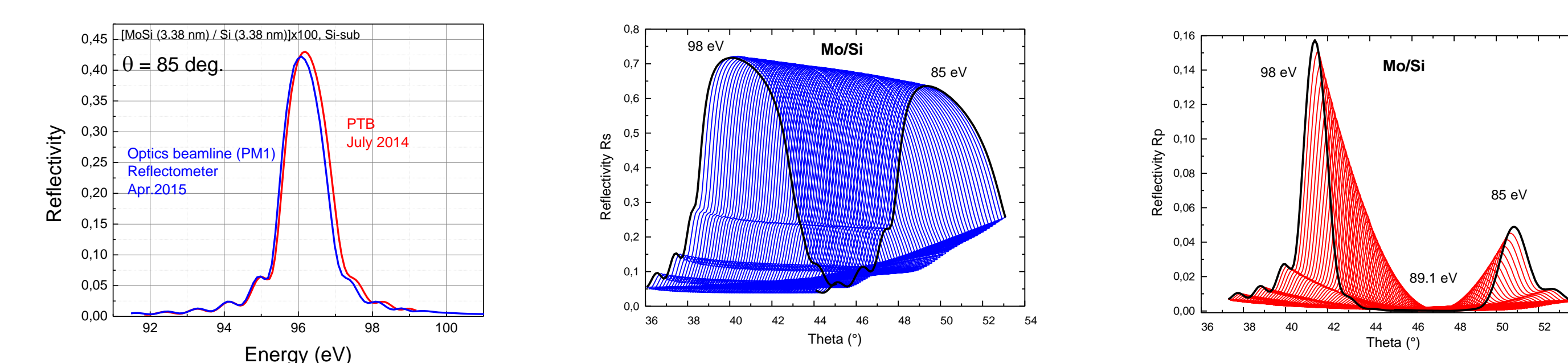
### TRIPOD SCAN RANGE X,Y,Z



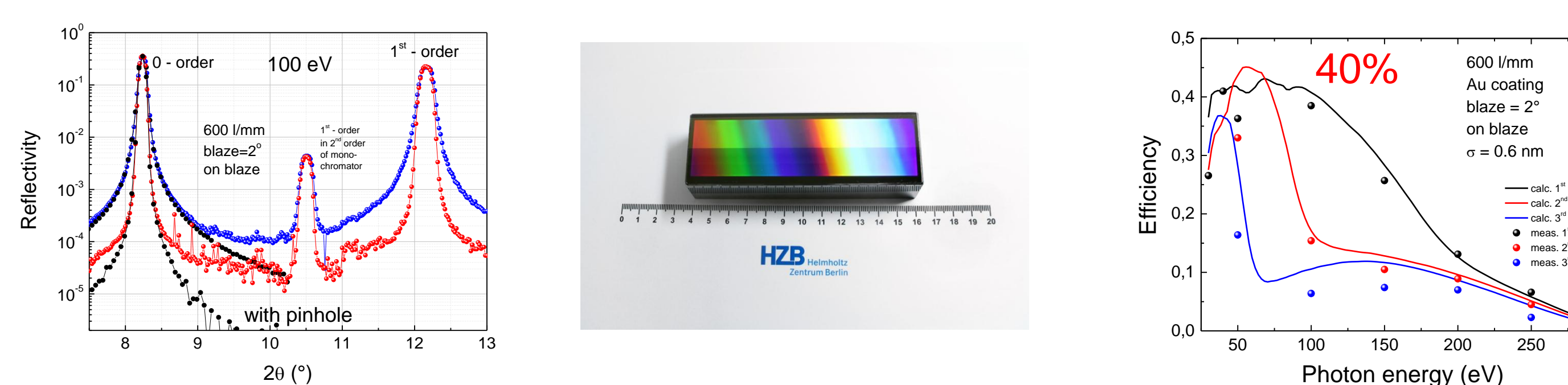
Axis	Hardware	Range	Pos. accuracy
Azimuth angle $\beta$	HUBER 430	-180° - 180°	3.6"
Sample angle $\theta$	HUBER 411	-90° - 270°	3.6"
Detector angle $2\theta$	HUBER 411	-180° - 180°	3.6"
Detector off-plane (2 axes)	Ceramic motors	-25 mm - 25 mm (-4° - 4°)	50 nm
Sample Adjustment Tx, Ty, Tz	Ceramic motors	-20 mm - 20 mm (not simul.)	500 nm
Sample Adjustment Rx, Ry, Rz	Ceramic motors	-10° - 10° (not simul.)	1"

## At-Wavelength Metrology

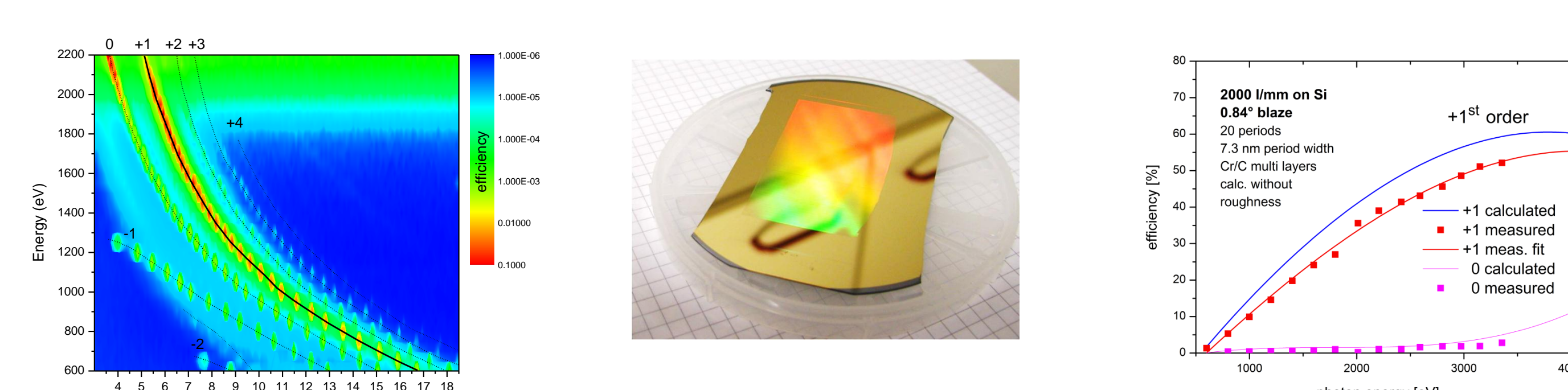
### Metrology on Multilayers



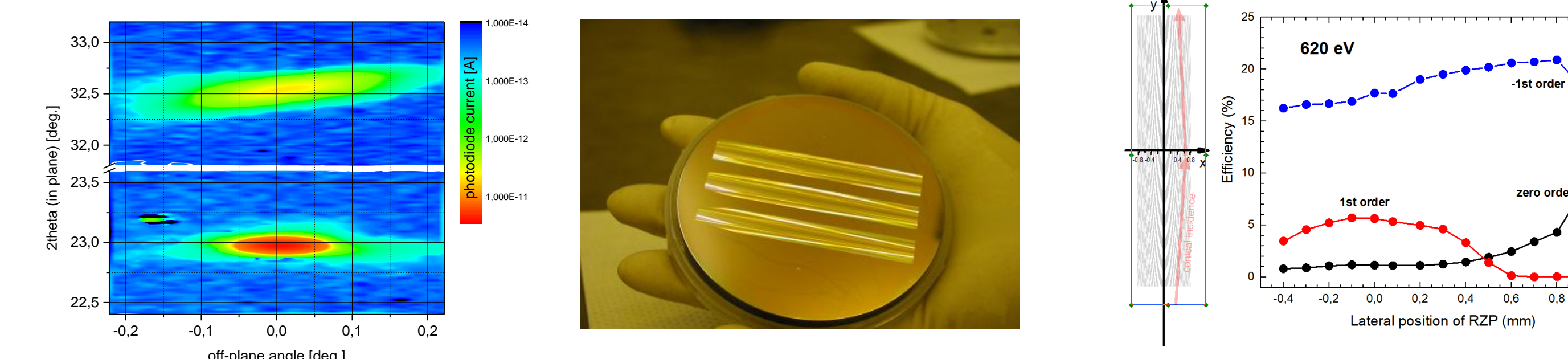
### Metrology on blazed gratings



### Metrology on blazed multilayer gratings

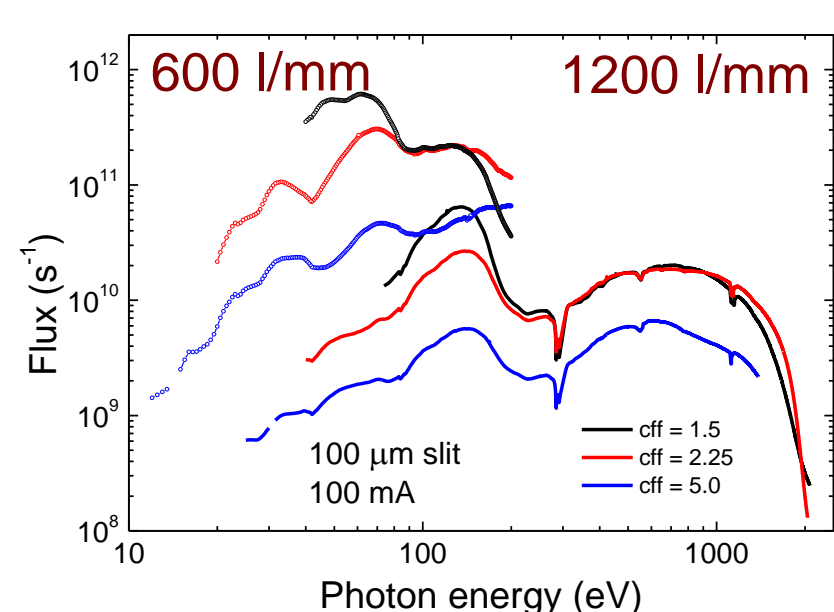


### Metrology on Reflection Zone Plates

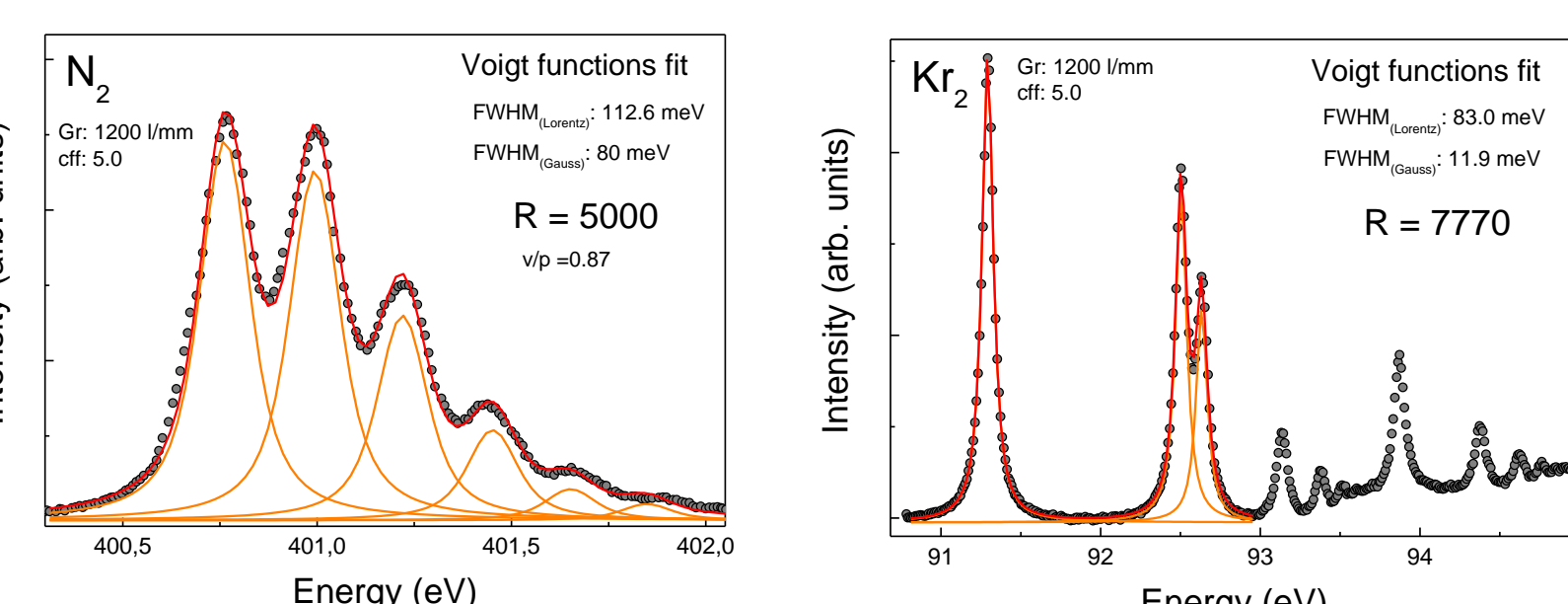


## Performance

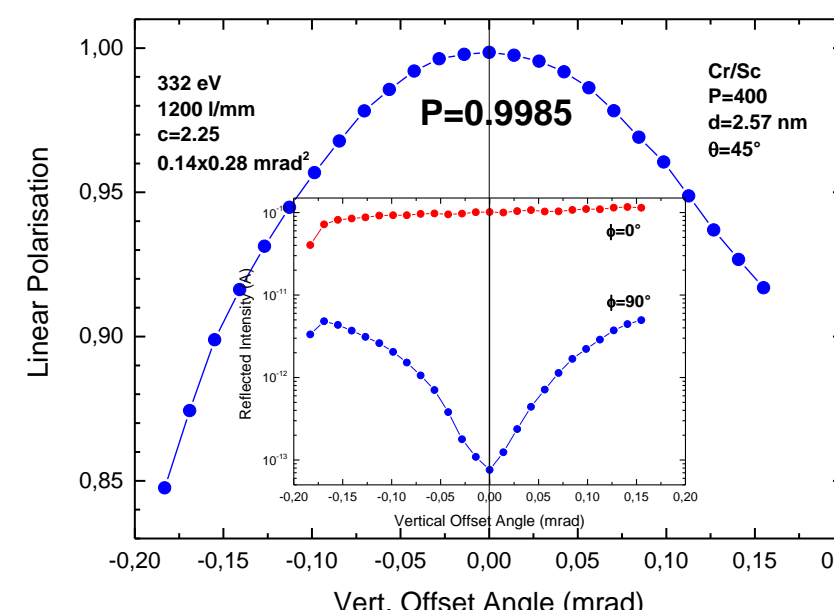
### Photon flux



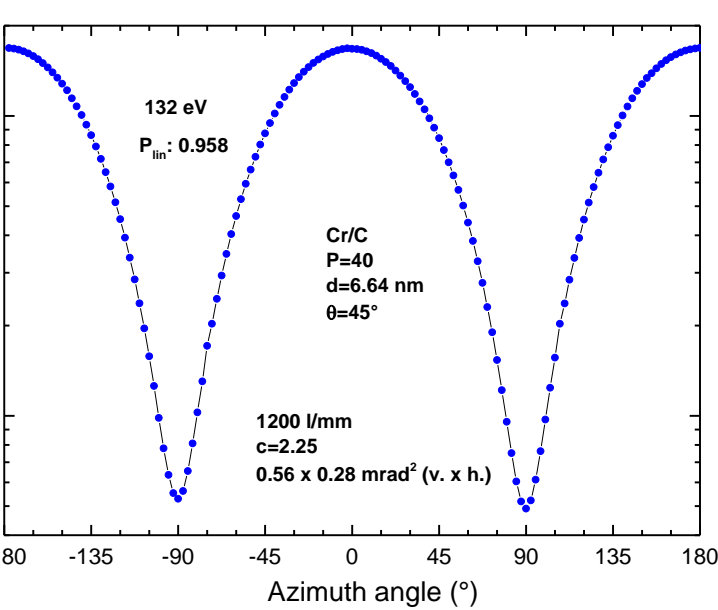
### Resolving Power



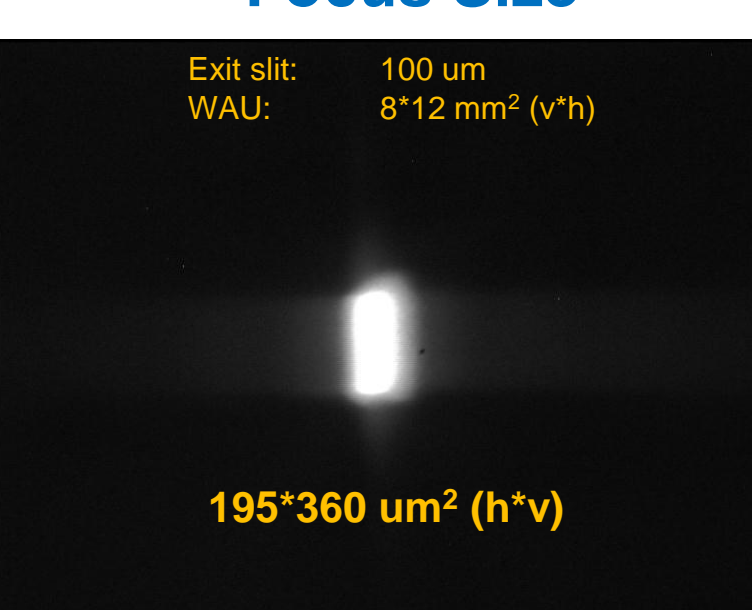
### Polarisation



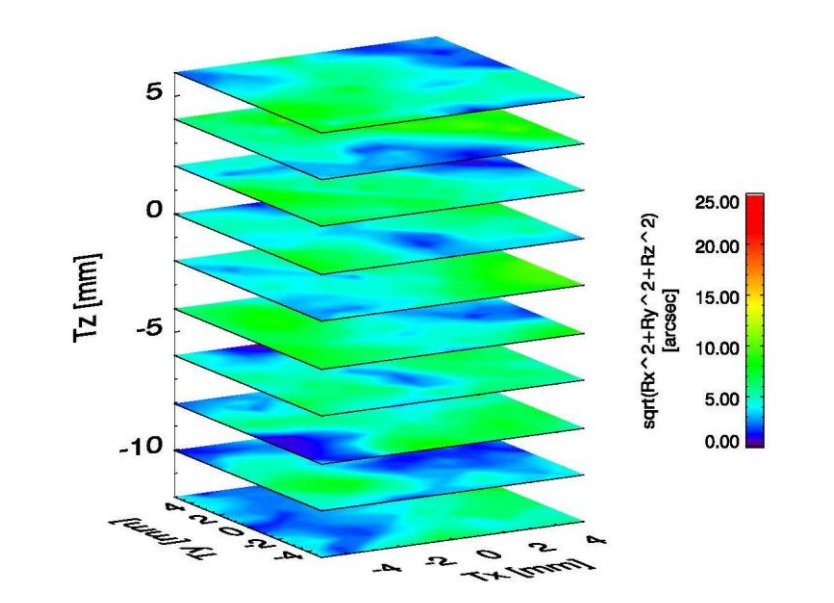
### Focus Size



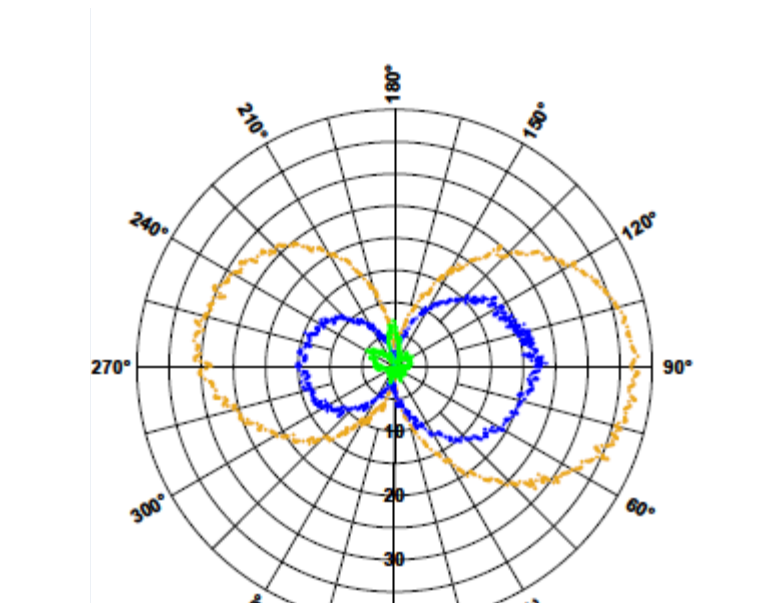
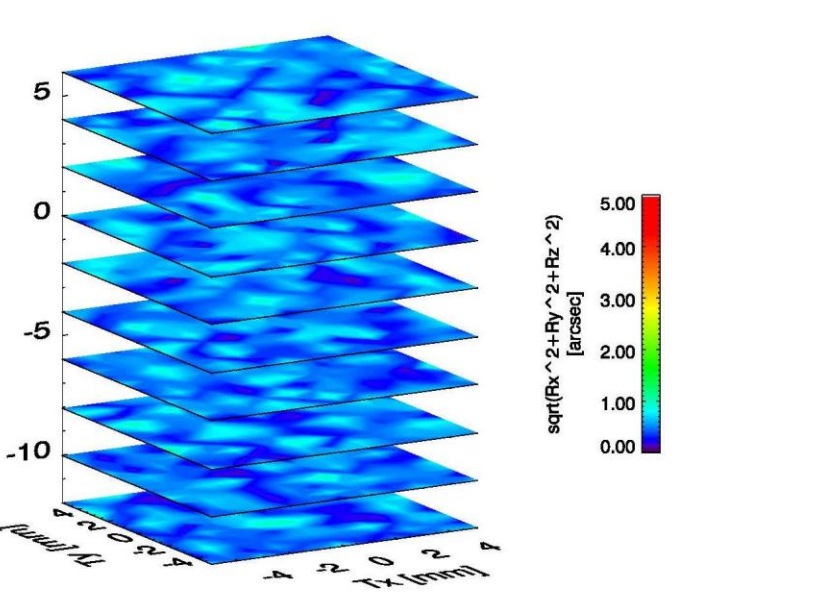
### Focus Size



### Positioning accuracy of the Tripod



### Autocollimation of $\phi$ -stage



### Alignment of Axes

Axis 1	Axis 2	Tilt (°)	Distance (mm)
$\theta$	2 $\theta$	179.979°	0.014
$\theta$	$\beta$	90.025°	0.049
2 $\theta$	$\beta$	89.994°	0.057

Sample pointing stability: 50  $\mu$ m / 0.025°

## Conclusions

- At-Wavelength metrology: powerful, indispensable tool for development, characterization and final control of UV/XUV optical elements
- At-Wavelength performance cannot be obtained by any other method
- HZB grating fabrication facility is well established now
- Attractive UV/XUV experimental beamline setup at BESSY-II operational
- Metrology on large-scale samples with versatile 11-axes UHV-reflectometer operational
- Ellipsometry, polarimetry possible with elliptically polarised bending magnet radiation
- Open for user operation
- Short-term access at 24 h / 7d operation possible

[1] A.A. Sokolov et al. An XUV Optics Beamline at BESSY II, Proc. of SPIE 9206, Advances in Metrology for X-Ray and EUV Optics V, 9206J-1-13 (2014)  
[2] F. Eggenstein et al. A reflectometer for at-wavelength characterization of XUV-reflection gratings, Proc. of SPIE 9206, 920607-1-12 (2014)  
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[4] B. Loechel et al. Installation of a technological center for highly efficient optical gratings at Helmholtz-Zentrum Berlin (HZB), J. Phys.: Conf. Ser. 425, 212012 (2013)  
[5] F. Schäfers, RAY - the BESSY raytrace program, (In: Springer Series in Modern Optical Sciences: Modern Developments in X-Ray and Neutron Optics) Vol. 137, 9-41 (2008)  
[6] F. Schäfers, R. Cimino, Soft X-ray reflectivity: from quasi-perfect mirrors to accelerator walls, Proc. Ecoloud'12, CERN-2013-002, p. 105-15 (2013)